

Search Notes

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Examiner

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Applicant(s)/Patent under
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WACHI, REIKO

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
349	106, 113, 114	9/14/2006	TT
257	59, 72	9/14/2006	TT

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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